

for Automotive Electronics

SPECIFICATIONS

Customer	天河星
Product Name	Wire Wound Chip Ferrite Inductor
Sunlord Part Number	AWL1608FSR21MTFY01
Customer Part Number	

[New Released, Revised]

SPEC No.: AWL02220001

[This SPEC is total 14 pages including specifications and appendix.]

[RoHS Compliant Parts]

Approved By	Checked By	Issued By
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[Precautions]

- 1. Magnetic materials shall be far away from parts to avoid impacts on their electrical characteristics.
- 2. Parts could be damaged by external mechanical pressure or stacked heavy objects, as well as strong shaking & dropping.
- 3. Please do not store parts in bulk to prevent coils and parts being damaged.
- 4. Oversized external force to parts on PCB may lead to parts being damaged or slipped off.
- 5. Please do not use parts on edge or top of PCB board in your design to avoid parts being damaged during PCB is moved.
- 6. Please use flux contained with resin since the highly acidic (Chlorine content more than 0.2 wt%) or water-soluble one could damage the insulation film of wires, then causing short circuit of parts.
- 7. Please do not use the brush to clean product or its surroundings. If you use the brush to clean product or its surroundings on PCB,copper wire may be broke, causing the product open .





1. Scope

1.1 Scope of parts

This specification applies to the AWL1608FSR21MTFY01 of Wire Wound Chip Ferrite Inductor for automotive electronics based on AEC-Q200.

1.2 Scope of application

Product numbers recorded in this specification are limited to applications with the following modules:

- (1) Prohibit using in Engine Control System.
- (2) Other applications please consult Sunlord.

2. Product Description and Identification (Part Number)

1) Description

Wire Wound Chip Ferrite Inductor

Product Identification (Part Number)

	608 <u>F</u> ② ③	<u>S</u> ④	<u>R21</u> ⑤	<u>M</u> ⑥	<u>I</u> ⑦	<u>F</u> ®	<u>Y01</u> ⑨	
① Type							② Ext	ernal Dimensions [L X W] (mm)
AWL	Wire		Chip Ind omotive	uctor			1608	
							4 Pro	duct Classification Code
3 Materia	l Code						S	Sn Plating
F		Fe	errite					One-faces Coating
⑤ Nominal	I Inductance	(nH)				- 	⑥ Ind	luctance Tolerance
Example		Nomin	al Value				М	±20%
R21		2	10				IVI	120/6
⑦ Packing	g					1	® HS	F Products
Т		Tape	& Reel			\		Hazardous Substance Free Products
9 Desig	n Code						7	

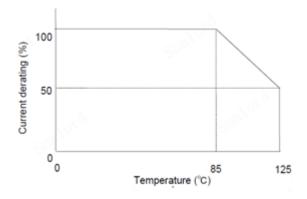
Electrical Characteristics

Part Number	Inductance	L Test Freq.	Max. DC Resistance	Max. Rated Current(*)	Min. Self-resonant Frequency
Units	nH	MHz	Ω	mA	MHz
Symbol	L	Freq.	DCR	lr	S.R.F
AWL1608FSR21MTFY01	210	10	0.150	1000	720

- Operating and storage temperature range (individual chip without packing): -40°C to +125°C
- Storage temperature range (packaging conditions): -10°C~+40°C and RH 70% (Max.)

Y01

As for AWL type, Rated Current is derated as following figure depending on the operating temperature Derating of Rated Current depend on Operating Temperature



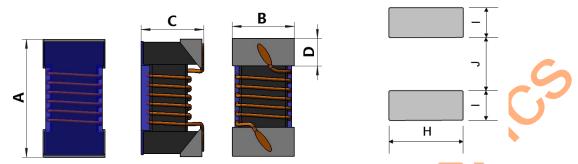
Α	В	С	D	H REF.	l REF.	J REF.
1.60±0.15	0.80±0.15	0.80±0.15	0.30±0.10	1.00	0.75	0.70

4. Shape and Dimensions

1) Dimensions: See the following.

2)

Unite: mm

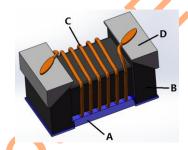


No.	Components	Material
Α	Coating	Ultraviolet epoxy resin
В	Core	Ferrite
С	Wire	Polyurethane system enameled copper wire
D	Electrodes	Ag with Ni and Sn plating

3) Electrode

Coplanarity:0.1mm Max.

4) Structure: See the following.



5. Test and Measurement Procedures

5.1 Test Conditions

Unless otherwise specified, the standard atmospheric conditions for measurement/test as:

- a. Ambient Temperature: 20±15°C
- b. Relative Humidity: 65%±20%
- c. Air Pressure: 86 KPa to 106 KPa

If any doubt on the results, measurements/tests should be made within the following limits:

- a. Ambient Temperature: 20±2°C
- b. Relative Humidity: 65%±5%
- c. Air Pressure: 86KPa to 106 KPa

5.2 Visual Examination

a. Inspection Equipment: 30X magnifier

5.3 Electrical Test

5.3.1 DC Resistance (DCR)

- a. Refer to Item 3.
- b. Test equipment: HIOKI3540 or equivalent.

5.3.2 Inductance (L)

- a. Refer to Item 3.
- b. Test equipment: Agilent4287A+Agilent16197A or equivalent.
- c. Test signal: -13dBm or 10mA
- d. Test frequency refers to Item 3.

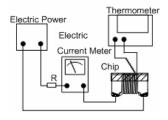
5.3.3 Self-Resonant Frequency (SRF)

- a. Refer to Item 3.
- b. Test equipment: Agilent E4991A+Agilent16197A and HP 8753E or equivalent.
- c. Test signal: -20dBm or 50mV

5.3.4 Rated Current

a. Refer to Item 3.

- Test equipment (see Fig.5.3.5-1): Electric Power, Electric current meter, Thermometer.
- Measurement method (see Fig. 5.3.5-1):
 - Set test current to be 0 mA.
 - 2. Measure initial temperature of chip surface.
 - Gradually increase voltage and measure chip temperature for corresponding current.
- Definition of Rated Current (Ir): Ir is direct electric current as chip surface temperature rose just 40 °C against chip initial surface temperature (Ta) (see Fig. 5.3.5-2)



Ta+40℃ Та 0 Rated current Ir (mA)

Fig. 5.3.5-2

Fig. 5.3.5-1

Reliability Test

Items	Requirements	Test Method(According to AEC-Q200)
6.1 Terminal Strength	No removal or split of the termination or other defects shall occur. Chip Mounting Pad Glass Epoxy Board	 Solder the chip to the testing jig (glass epoxy board) using eutectic solder. Then apply a force in the direction of the arrow. 7N force, Keep time: 10(+1) sec. Speed: 1.0 mm/s.
6.2 Board Flex	No visible mechanical damage. R10 Unit: mm R10 45 Flexur	 Solder the chip to the test jig (glass epoxy board—1.6mm) using a eutectic solder. Then apply a force in the direction shown as left. Flexure: 2mm. Pressurizing speed: 0.5mm/sec. Keep time: 60(+5) sec.
7.3 Vibration	No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic Cu pad Solder mask Glass Epoxy Board	 Solder the chip to the testing jig (glass epoxy board) using eutectic solder. The chip shall be subjected to a simple harmonic motion having total amplitude of 1.5mm, the vibration acceleration of 5g, the frequency being varied uniformly between the approximate limits of 10 and 2000 Hz. The frequency range from 10 to 2000 Hz and return to 10 Hz shall be traversed in approximately 20 minute. This motion shall be applied for a period of 4 hours in each 3 mutually directions (total of 12 hours).
6.4 Mechanical Shock	No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic	 Half sinusoid, the peak acceleration: 100g. Pulse width: 6 ms. This motion shall be applied for 6 times in each 3 mutually directions (total of 18 times).
6.5 Resistance to soldering heat	No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic	Re-flowing Profile: 260°C 200°C 190°C 150°C 90±30sec.



Items	Requirements	Test Method(According to AEC-Q200)
		Method 1:① pretreatment:155°C,4h ② 235°C,5(-0.5,+0)s ③ Solder:Sn/3.0Ag/0.5Cu ④ Flux: 25% resin and 75% ethanol in weight. Method 2:① Steam aging:8h
6.6 Solderability	①Wetting shall be exceeded 90%coverage	② 235°C,5(-0.5,+0)s ③ Solder:Sn/3.0Ag/0.5Cu ④ Flux: 25% resin and 75% ethanol in weight. Method 3:① Steam aging:8h
		② 260°C,7(-0.5,+0.5)s ③ Solder:Sn/3.0Ag/0.5Cu ④ Flux: 25% resin and 75% ethanol in weight.
6.7 Low Temperature Storage	 No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic 	 Temperature: -40±2°C Duration: 1000⁺²⁴ hours The chip shall be stabilized at normal condition for 1~2 hours before measuring.
6.8 High Temperature Exposure	 No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic 	 Temperature: 125±2°C Duration: 1000*24 hours The chip shall be stabilized at normal condition for 1~2 hours before measuring.
6.9 Temperature Cycling	① No visible mechanical damage ② Inductance change: Within ±5% ③ DCR :Satisfy electrical characteristic +125°C Ambient Temperature -40°C 30 min. 20s (max.)	 Temperature, Time: -40°C for 30±3 min →+125°C for 30±3min Transforming interval: 20 sec. (max.) Tested cycle: 500 cycles The chip shall be stabilized at normal condition for 1~2 hours before measuring.
6.10 Moisture Resistance	No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic	 25°C→65°C,90%~100%RH,2.5h. 65°C,90%~100%RH,3h. 65°C→25°C,80%~100%RH,2.5h. 25°C→65°C,90%~100%RH,2.5h. 65°C,90%~100%RH,3h. 65°C→25°C,80%~100%RH,2.5h. 25°C,90%~100%RH,8h,24hours of 1cycle. Tested cycle: 10 cycles The chip shall be stabilized at normal condition for 1~2 hours before measuring.
6.11 Operational Life	No visible mechanical damage Inductance change: Within ±5% DCR :Satisfy electrical characteristic	 Temperature: 125±2°C. Duration: 500⁺²⁴ hours. Applied current: Rated current. The chip shall be stabilized at normal condition for 1~2 hours before measuring.
6.12 Temperature Characteristics	① No visible mechanical damage② Inductance change: Within ±5%	 ① Temperature range: -40℃~+125℃. ② Reference temperature: +20℃.

Items	Requirements	Test Method(According to AEC-Q200)
6.13 Flammability (External Flame)	 t1 or t2:≤10s. t1 plus t2 for the 5 specimens:≤50s. t2+t3 for each specimen:≤30s. no afterflame or afterglow of any specimen up to the holding clamp. no cotton indicator ignited by flaming particles or drops. 	MIL-STD-202 Method 111、 UL94
6.14 Resistance to Solvents	After test, the samples no fell off, fade, dim, transposition and others phenomenon.	MIL-STD-202 Method 215
6.15 ESD Test	 No visible mechanical damage Inductance change:Within ±5% DCR :Satisfy electrical characteristic 	Contact discharge, 8 KV, twice, one in the positive polarity and the other in the negative polarity.
6.16 Biased Humidity	No visible mechanical damage Inductance change:Within ±5% DCR :Satisfy electrical characteristic	 Temperature: 85±2°C. Humidity: 85% RH. Duration: 1000⁺²⁴ hours. The chip shall be stabilized at normal condition for 1~2 hours before measuring.

7. Packaging and Storage

7.1 Packaging

There are two types of packaging for the chip inductors. Please specify the packing code when ordering.

Tape Carrier Packaging:

Packaging code: T

- Tape carrier packaging are specified in attached figure Fig.7.1-1~5
- Tape carrier packaging quantity please see the following table: b.

c.

Туре	1608	
Tape	Paper	Таре
Quantity	Standard	3К

(1) Taping Drawings (Unit: mm)

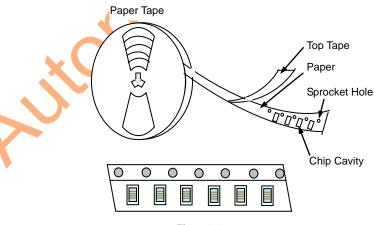
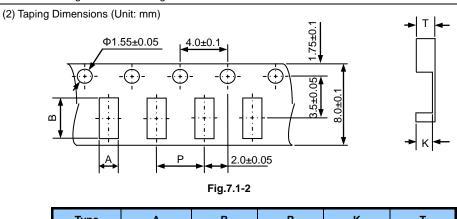


Fig. 7.1-1

Remark: The sprocket holes are to the right as the tape is pulled toward the user.



Турс	^	ם		IX	•
1608	1.05±0.05	1.85±0.05	4.0±0.10	0.98±0.05	1.02±0.05

(3) Leader and blank portion

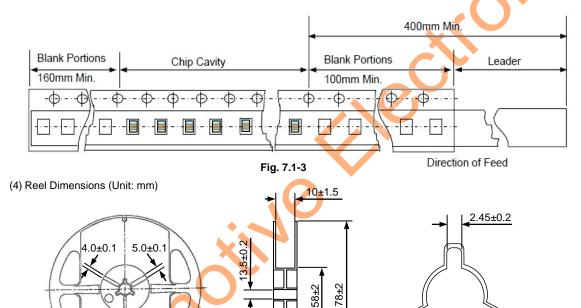
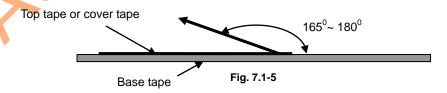


Fig. 7.1-4

(5) Peeling off force: 10gf to 70gf in the direction show below.



7.2 Storage

- The solderability of the external electrode may be deteriorated if packages are stored where they are exposed to high humidity.
- The solderability of the external electrode may be deteriorated if packages are stored where they are exposed to dust of harmful gas (e.g. HCl, sulfurous gas of H₂S)
- Packaging material may be deformed if package are stored where they are exposed to heat of direct sunlight.
- Minimum packages, such as polyvinyl heat-seal packages shall not be opened until they are used. If opened, use the reels as soon as possible.
- Solderability shall be guaranteed for 12 months from the date of delivery on condition that they are stored at the environment specified in specification. For those parts, which passed more than 12 months shall be checked solder-ability before use.



Warning and Attentions

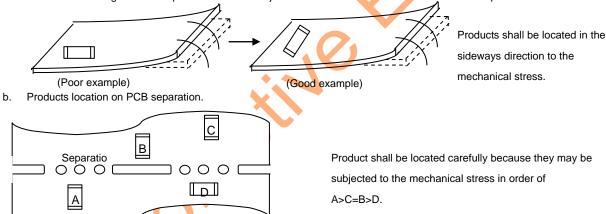
8.1 Precautions on Use

- Always wear static control bands to protect against ESD.
- b. Any devices used (soldering iron, measuring instruments) should be properly grounded.
- Use non-magnetic tweezers when handing the chips. C.
- d. Pre-heating when soldering, and refer to the recommended condition specified in specification.
- Don't apply current in excess of the rated current value. It may cause damage to components due to over-current.
- f. Keep clear of anything that may generate magnetic fields such as speakers, coils.
- When soldering, the electrical characteristics may be varied due to hot energy and mechanical stress. g.
- When coating products with resin, the relatively high resin curing stress may change the electrical characteristics. For exterior coating, select resin carefully so that electrical and mechanical performance of the product is not affected. Before using, please evaluate reliability with the product mounted in your application set.
- i. When mount chips with adhesive in preliminary assembly, do appropriate check before the soldering stage, i.e., the size of land pattern, type of adhesive, amount applied, hardening of the adhesive on proper usage and amounts of adhesive to use.
- Mounting density: Add special attention to radiating heat of products when mounting other components nearby. The excessive heat by other products may cause deterioration at joint of this product with substrate.
- Since some products are constructed like an open magnetic circuit, narrow spacing between components may cause magnetic
- Please do not give the product any excessive mechanical shocks in transportation.
- Please do not touch wires by sharp terminals such as tweezers to avoid causing any damage to wires.
- Please do not add any shock and power to the soldered product to avoid causing any damage to chip body.
- Please do not touch the electrodes by naked hand as the solderability of the external electrodes may deteriorate by grease or oil on

8.2 PCB Bending Design

The following shall be considered when designing and laying out PCB's.

PCB shall be designed so that products are not subjected to the mechanical stress from board warp or deflection.



When splitting the PCB board, or insert (remove) connector, or fasten thread after mounting components, care is required so as not to give any stress of deflection or twisting to the board. Because mechanical force may cause deterioration of the bonding strength of electrode and solder, even crack of product body. Board separation should not be done manually, but by using appropriate devices.

8.3 Recommended PCB Design for SMT Land-Patterns

When chips are mounted on a PCB, the amount of solder used (size of fillet) and the size of PCB Land-Patterns can directly affect chip performance (such as Q). And they can also cause other soldering question (such as offset and side lap). Therefore, the following items must be carefully considered in the design of solder land patterns.

- Please use the PCB pad and solder paste we recommend, and contact us in advance if they need to be changed.
- Please use flux contained with resin since the highly acidic (Chlorine content more than 0.2 wt%) or water-soluble one could damage the insulation film of wires, then causing short circuit of parts.
- The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets.
- When more than one part is jointly soldered onto the same land or pad, the pad must be designed that each component's soldering point is separated by solder-resist.

Recommended land dimensions please refer to product specification.

9. Visual inspection standard of product

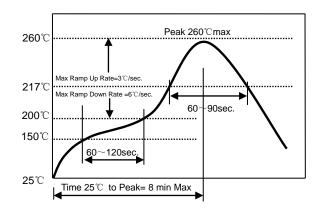
Eff	File No:	Applied to Wire Wound Ceramic Inductor Series	
No.	Defect Item	Graphic Schematic Drawing	Rejection identification Criteria
1	Wire off/ Welding Spot Off		The solder joint Welding Spot of wire break away from electrodes, or over the electrodes.
2	Solder misplace		Solder joints are not at electrode side but at the coating side or flank.
3	Coating misplace		Coating at flank
			Coating at electrodes side

10. Recommended Soldering Technologies

This product is only for reflow soldering and iron soldering.

10.1 Re-flowing Profile

- △ Preheat condition: 150~200 ℃/60~120sec.
- △ Allowed time above 217C: 60~90sec.
- △ Max temp: 260°C
- △ Max time at max temp: 10sec.
- Solder paste: Sn/3.0Ag/0.5Cu \triangle
- Allowed Reflow time: 2 times max.



1. The reflow profile in the above table is only for qualification and is not meant to specify board assembly profiles. Actual board assembly profiles must be based on the customer's specific board design, solder paste and process, and should not exceed the parameters as the Reflow profile shows.

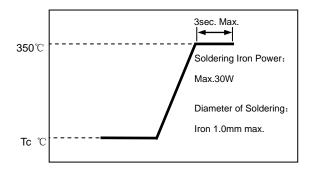
2. After reflow soldering uv glue appearance have slight color change.

10.2 Iron Soldering Profile

△ Iron soldering power: 30W Max.△ Preheat condition: 150°C/60sec.

△ Soldering tip temperature: 350°C Max.

[Note: Take care not to apply the tip of the soldering iron to the terminal electrodes.]



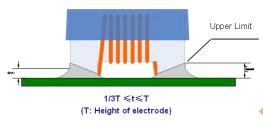
10.3 Maintenance of heat gun (for your reference)

△ Power output: 30W△ Temperature: 350°C Max

△ Heat time: More than 5 seconds heating may cause short circuit of parts.

11. Solder Volume

Solder shall be used not to exceed as shown below.



Accordingly increasing the solder volume, the mech

- a. anical stress to chip is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance.
- b. Before soldering, please ensure that the solder should not adhere to the wire part of chip.
- c. Please pay particular attention to whether there is flux remaining on surface of the wire part of chip after subjected to reflow soldering since this may causing short circuit of parts.

12. Cleaning

Products shall be cleaned on the following conditions:

- a. Cleaning temperature shall be limited to 60°C Max. (40°C Max. for fluoride and alcohol type cleaner.)
- b. Ultrasonic cleaning shall comply with the following conditions, avoiding the resonance phenomenon at the mounted products and PCB.

Power: 20W/I Max.

Frequency: 28 KHz to 40 KHz

Time: 5 minutes Max

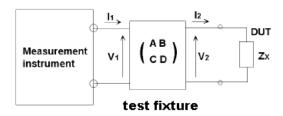
c. Cleaner

- . Alternative cleaner
 - Isopropyl alcohol (IPA)
 - HCFC-225
- ii. Aqueous agent
 - Surface Active Agent Type (Clean through-750H)
 - Hydrocarbon Type (Techno Cleaner-335)
 - Higher Alcohol Type (Pine Alpha ST-100S)

 - X Alkali saponification shall be diluted to 20% volume with de-ionized water.
 - * Please contact our technical service department before using other cleaner.
- d. There shall be no residual flux and residual cleaner after cleaning. In the case of using aqueous agent, product shall be dried completely after rinse with de-ionized water in order to remove the cleaner.
- e. Some products may become slightly whitened. However, product performance or usage is not affected.
- f. Please take care of winding part while cleaning.
- g. After cleaning, parts could be subjected to the next reflow soldering till the solvent remaining on surface of parts being volatilized.

13. Measuring Method of Inductance

Residual elements and stray elements of test fixture can be described by F-parameter as shown in the following:



$$\begin{bmatrix} V_1 \\ I_1 \end{bmatrix} = \begin{bmatrix} A & B \\ C & D \end{bmatrix} \begin{bmatrix} V_2 \\ I_2 \end{bmatrix}$$
$$\begin{bmatrix} V_1 \\ I_1 \end{bmatrix} = \begin{bmatrix} AV_2 + BI_2 \\ CV_2 + DI_2 \end{bmatrix}$$

Measured open impedance: $Zom = \frac{A}{C}$

Measured short impedance: $Z_{SM} = \frac{B}{D} \approx -Z_{SC}$ (when uses short chip to short)

Measured short ship impedance: Zsc

Measured value: Zxm=V₁/I₁ Impedance of DUT: Zx=V₂/I₂

The relation between Zx and Zom, Zsm, Zxm is shown in the following:

$$Zx = \frac{V_2}{I_2} = \frac{D}{A} * \frac{\frac{V_1}{I_1} - \frac{B}{D}}{1 - \frac{V_1}{I_1} * \frac{C}{A}} = \frac{D}{A} * \frac{Zxm - \frac{B}{D}}{1 - Zxm * \frac{C}{A}} = \frac{D}{A} * \frac{Zxm - Zsm}{1 - Zxm / Zom}$$

Lx should be calculated with the following equation:

$$Lx = \frac{\text{Im}(Zx)}{2\pi f} = \frac{\text{Im}(Zxm + Zsc)}{2\pi f} = \frac{\text{Im}(Zxm)}{2\pi f} + \frac{\text{Im}(Zsc)}{2\pi f} = Lxm + Lsc$$

Lxm: measured chip inductor inductance

Lsc: measured short chip inductance

Lx: Inductance of chip inductor

Compensation Value (Lsc) of short chip

Series	Compensation Value	
AWL1608FS□□□□TFY01	0.9nH	

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